

ABSTRACT OF THE DISCLOSURE

A highly reliable method for screening a multi-layer ceramic electronic component, in which multi-layer ceramic electronic components having inner-structural defects and a reduced useful life are efficiently detected and removed. In this method, after applying an AC voltage to a multi-layer ceramic electronic component, a DC voltage is applied thereto. Then, by measuring the insulation-resistance value of the electronic component obtained when the DC voltage is applied, the quality of the multi-layer ceramic electronic component is checked. The applied AC voltage is in a range of 40 to 80% or 50 to 70% of a breakdown voltage. The applied DC voltage is between approximately a rated voltage and approximately twice the rated voltage. This method can, for example, be applied to the screening of a multi-layer ceramic capacitor.

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